

PDFN5060 Plastic-Encapsulate MOSFETS

Features

- $V_{DS}=80V$
- $I_D=110A$
- $R_{DS(on)}@V_{GS}=10V < 5.2m\Omega$
- High density cell design for ultra low R_{dson}
- Advanced Split Gate Trench Technology
- Fast Switching Speedze

Drain-source Voltage

80 V

Drain Current

110 Ampere

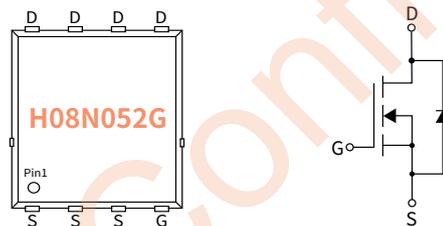
Applications

- DC-DC Converters
- Uninterruptible power supply
- Power switching application

Mechanical Data

- Case: PDFN5060
Molding compound meets UL 94V-0 flammability rating, RoHS-compliant,halogen-free
- Terminals: Solder plated, solderable per MIL-STD-750,Method 2026

Function Diagram



Ordering Information

PACKAGE	PACKAGE CODE	UNIT WEIGHT(g)	REEL(pcs)	BOX(pcs)	CARTON(pcs)	DELIVERY MODE
PDFN5060	R3	0.09	5000	10000	80000	13"

Maximum Ratings (Ta=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	VALUE
Drain-source Voltage	V_{DS}	V	80
Gate-source Voltage	V_{GS}	V	± 20
Drain Current	I_D	A	110
Pulsed Drain Current ⁽¹⁾	I_{DM}	A	440
Total Power Dissipation	P_D	W	120
Single pulse avalanche energy ⁽²⁾	EAS	mJ	272
Junction temperature	T_J	°C	-55 ~+150
Storage temperature	T_{stg}	°C	-55 ~+150
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	°C / W	1.04

● Static Parameter Characteristics (Tj=25°C Unless otherwise specified)

PARAMETER	SYMBOL	Condition	UNIT	Min	Typ	Max
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	V	80	—	—
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=80V, V_{GS}=0V$	μA	—	—	1.0
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	nA	—	—	± 100
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	V	2	3	4
Static Drain-Source On-Resistance ⁽³⁾	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	m Ω	—	4.2	5.2

● Dynamic Parameters

PARAMETER	SYMBOL	Condition	UNIT	Min	Typ	Max
Input Capacitance	C_{iss}	$V_{DS}=40V, V_{GS}=0V, f=1MHz$	pF	—	3818	—
Output Capacitance	C_{oss}			—	515	—
Reverse Transfer Capacitance	C_{rss}			—	21	—

● Switching Parameters

PARAMETER	SYMBOL	Condition	UNIT	Min	Typ	Max
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DD}=40V, I_D=50A, R_{GEN}=3\Omega$	nS	—	17	—
Turn-on Rise Time	t_r		nS	—	39	—
Turn-off Delay Time	$t_{D(off)}$		nS	—	64	—
Turn-off fall Time	t_f		nS	—	42	—
Total Gate Charge	Q_g	$V_{DS}=40V, I_D=50A, V_{GS}=10V$	nC	—	42	—
Gate-Source Charge	Q_{gs}		nC	—	15	—
Gate-Drain Charge	Q_{gd}		nC	—	20	—

● Drian-Source Diode Characteristics

PARAMETER	SYMBOL	Condition	UNIT	Min	Typ	Max
Diode Forward Voltage	V_{SD}	$I_S=110A, V_{GS}=0V$	V	—	—	1.2
Maximum Body-Diode Continuous Current	I_S	—	A	—	—	110
Reverse Recovery time	T_{rr}	$I_{SD}=110A, di/dt=100A/us$	nS	—	45	—
Reverse Recovery Charge	Q_{rr}		nC	—	56	—

Note :

(1)Repetitive Rating: Pulse width limited by maximum junction temperature.

(2)EAS condition : Tj=25°C ,VDD=40V,VG=10V,L=0.5mH,IAS=33A,Rg=25 Ω .

(3)Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.

● Ratings And Characteristics Curves (Ta=25°C Unless otherwise specified)

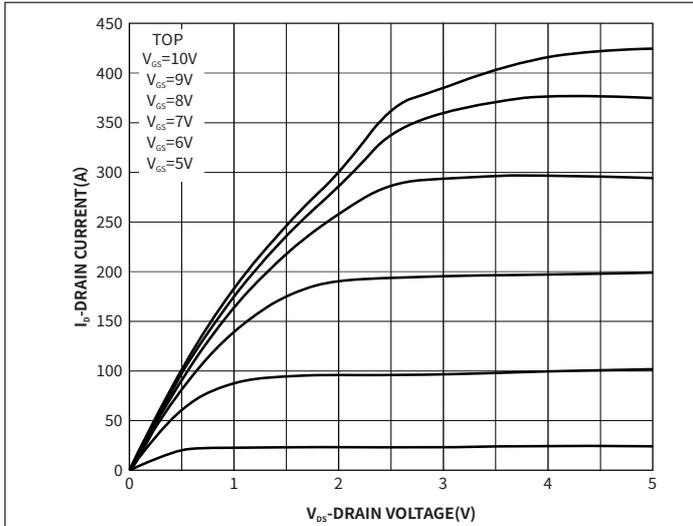


Fig.1 Output Characteristics

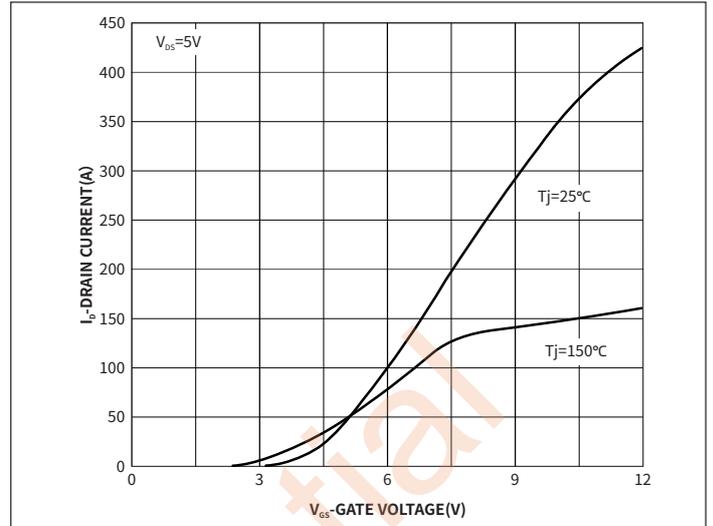


Fig.2 Transfer Characteristics

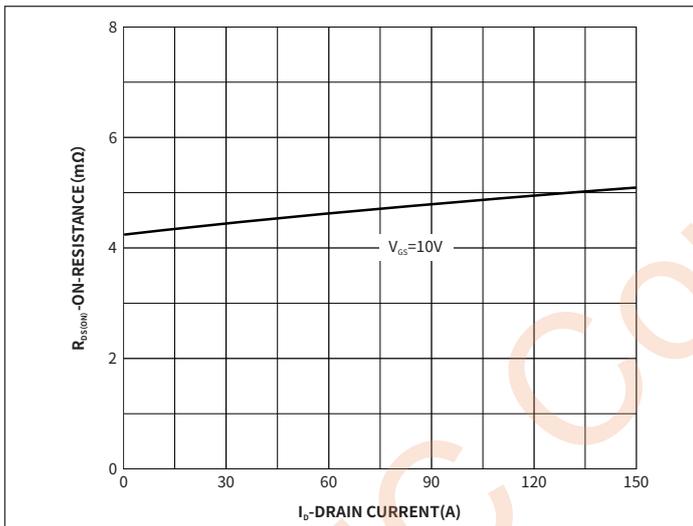


Fig.3 On-Resistance vs. Drain Current and Gate Voltage

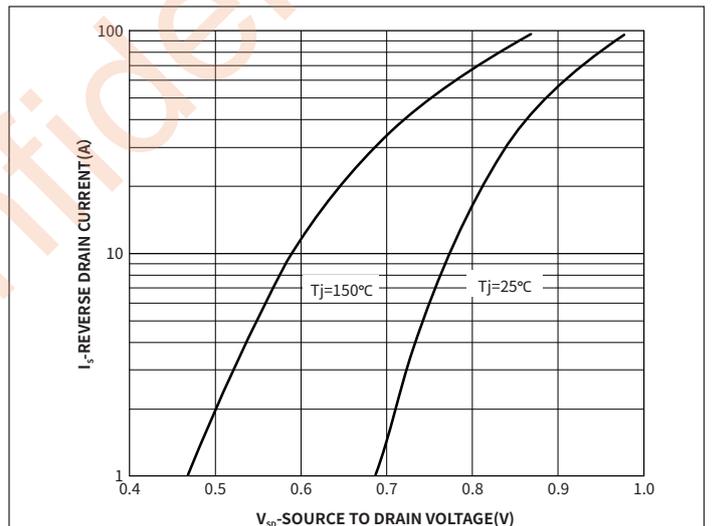


Fig.4 Typical Body-Diode Forward Characteristics

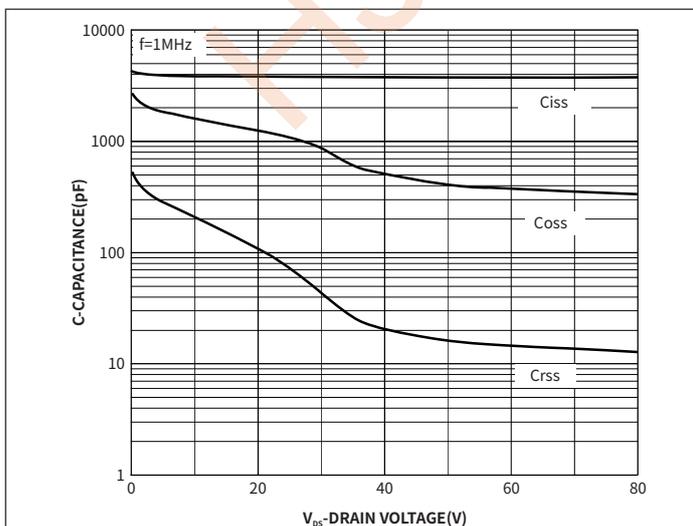


Fig.5 Capacitance Characteristics

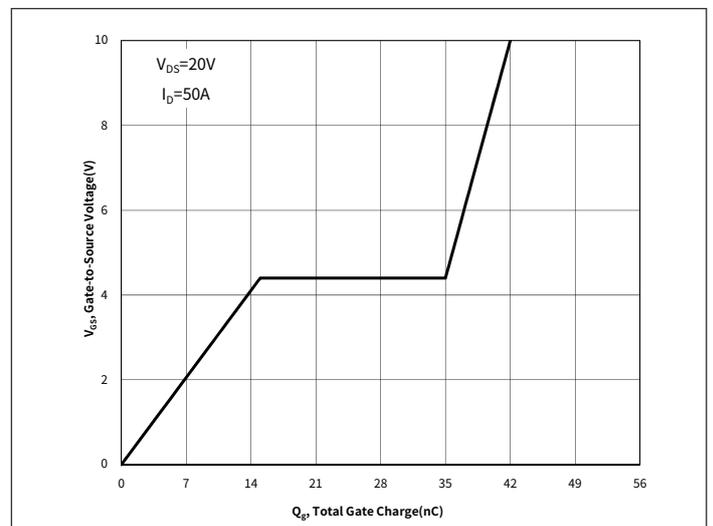


Fig.6 Gate Charge

● Ratings And Characteristics Curves (Ta=25°C Unless otherwise specified)

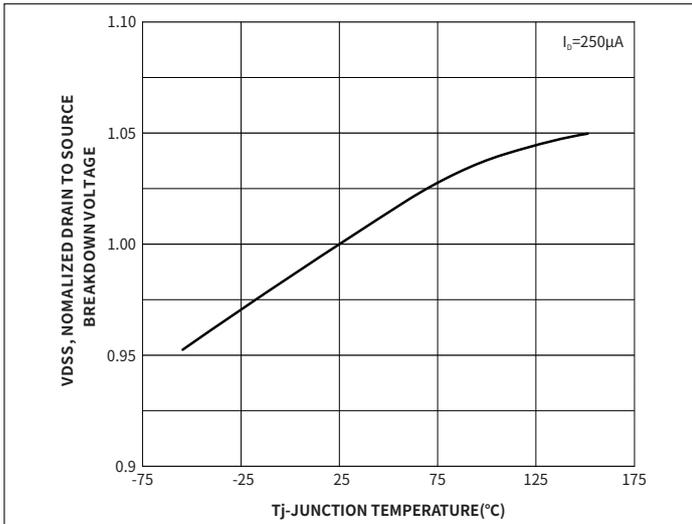


Fig.7 V(BR)DSS vs. Junction Temperature

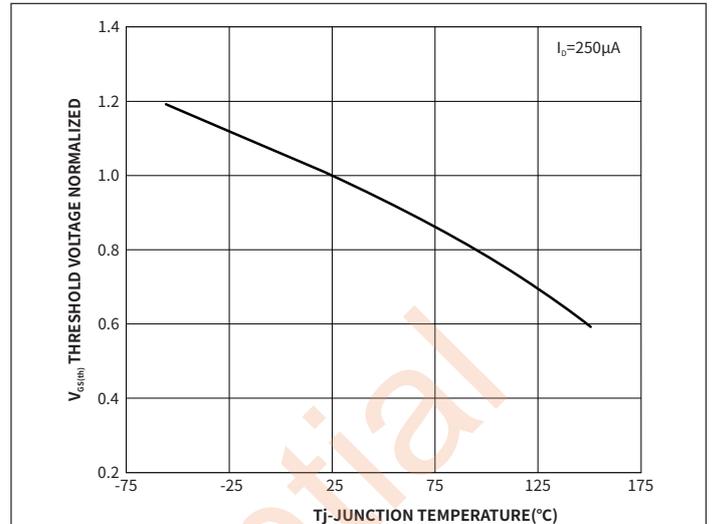


Fig.8 Gate Threshold Variation vs. Tj

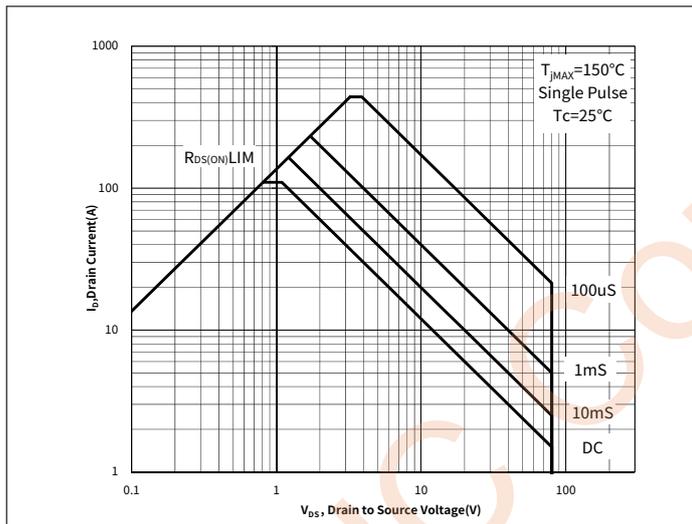


Fig.9 Safe Operation Area

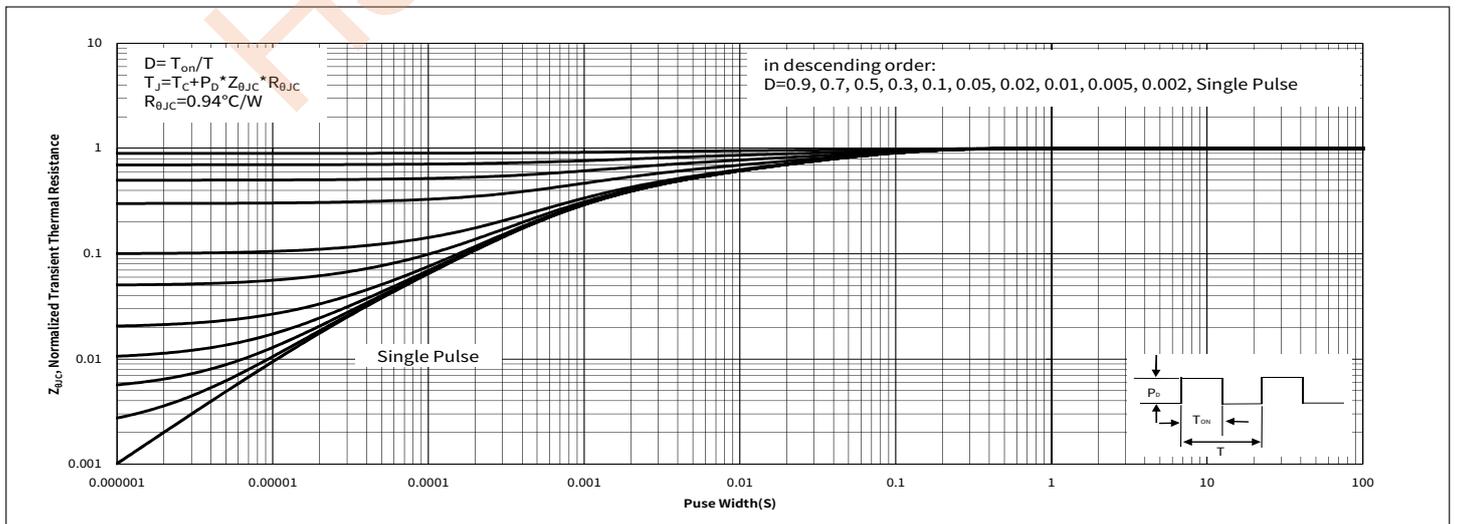
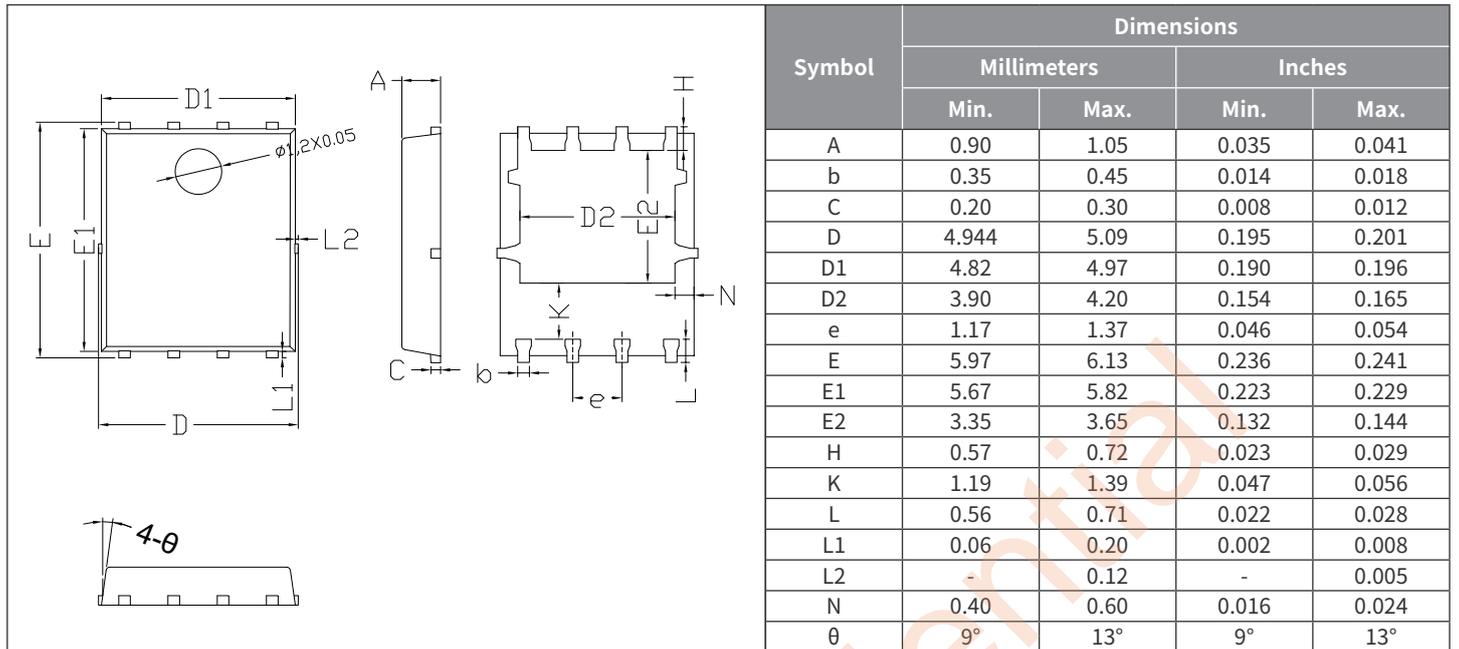
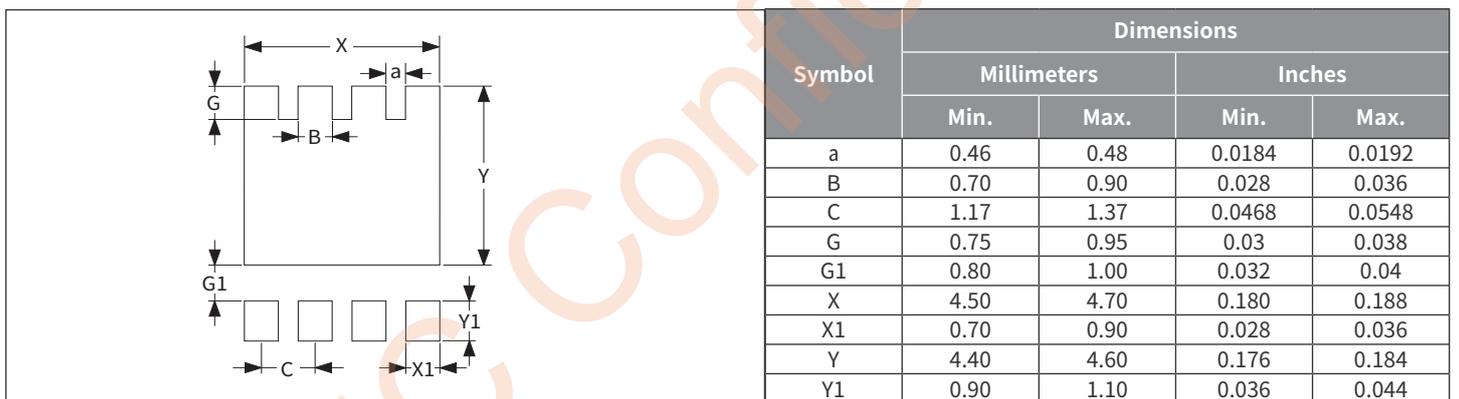


Fig.10 Normalized Maximum Transient Thermal Impedance

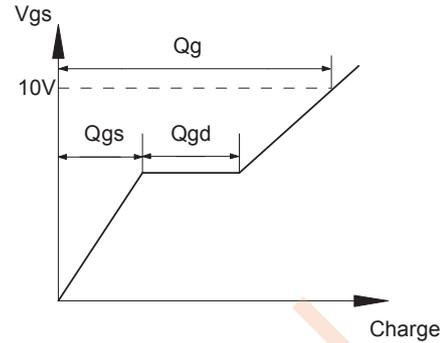
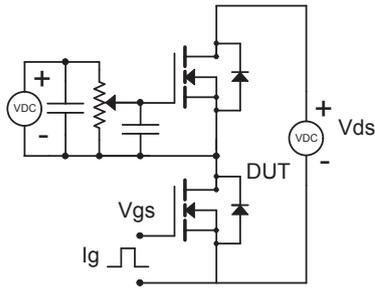
● **Package Outline Dimensions** (PDFN5060)



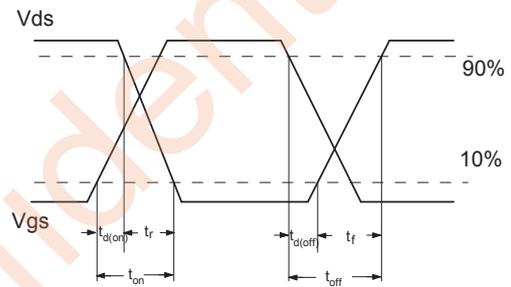
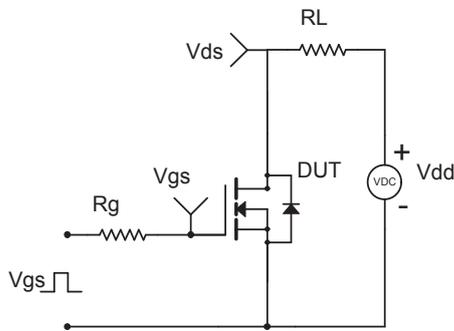
● **Suggested Pad Layout**



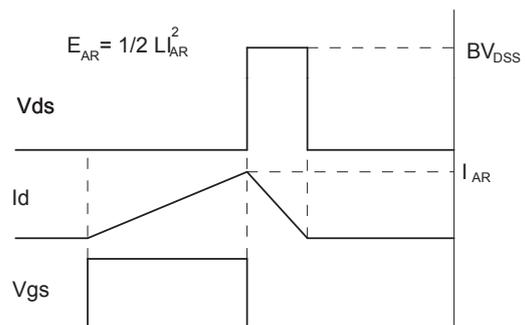
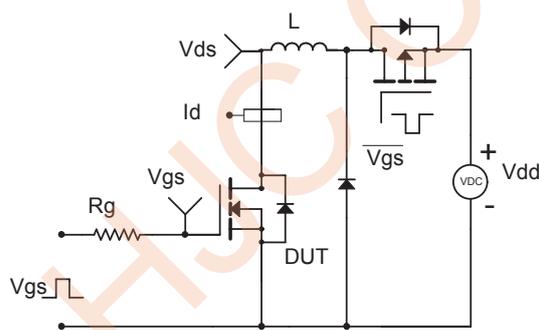
1. Gate Charge Test Circuit & Waveforms



2. Resistive Switching Test Circuit & Waveforms



3. Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



4. Diode Recovery Test Circuit & Waveforms

